

## September 2007 UniFET

# FDP80N06 N-Channel MOSFET 60V, 80A, $10m\Omega$

### **Features**

- $R_{DS(on)} = 8.5 m\Omega$  ( Typ.)@  $V_{GS} = 10V$ ,  $I_D = 40A$
- Low gate charge(Typ. 57nC)
- Low C<sub>rss</sub>(Typ. 145pF)
- · Fast switching
- · Improved dv/dt capability
- · RoHS compliant

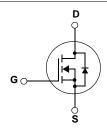


### **Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pluse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies, active power factor correction, electronic lamp ballast based on half bridge topology.





### **MOSFET Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted\*

Symbol	Parameter			Ratings	Units
V <sub>DSS</sub>	Drain to Source Voltage			60	V
V <sub>GSS</sub>	Gate to Source Voltage			±20	V
	Drain Current	-Continuous (T <sub>C</sub> = 25°C)		80	^
ID	Diamounem	-Continuous (T <sub>C</sub> = 100°C)		65	A
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	320	А
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note:		(Note 2)	480	mJ
I <sub>AR</sub>	Avalanche Current		(Note 1)	80	Α
E <sub>AR</sub>	Repetitive Avalanche Energy		(Note 1)	17.6	mJ
dv/dt	Peak Diode Recovery dv/d	dt	(Note 3)	4.5	V/ns
В	Power Dissipation	(T <sub>C</sub> = 25°C)		176	W
$P_{D}$	Power Dissipation	- Derate above 25°C		1.17	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Te	mperature Range		-55 to +175	°C
T <sub>L</sub>	•	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	°C

<sup>\*</sup>Drain current limited by maximum junction temperature

### **Thermal Characteristics**

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.85	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	C/VV

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### Package Marking and Ordering Information $T_C = 25^{\circ}C$ unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP80N06	FDP80N06	TO-220	-	-	50

### **Electrical Characteristics**

Symbol	Parameter Test Conditions		Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250\mu A, V_{GS} = 0V, T_J = 25^{\circ}C$	60	-	-	V
ΔBV <sub>DSS</sub> / ΔΤ <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.075	-	V/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 60V, V_{GS} = 0V$	-	-	1	
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 48V, T_{C} = 150^{\circ}C$	-	-	10	μА
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA

### On Characteristics

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250\mu A$	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 40A$	-	8.5	10	mΩ
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 25V, I_D = 40A$ (Note 4)	-	67	ı	S

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 25V V 0V	-	2450	3190	pF
Coss	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz	-	910	1190	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 11/11/2	-	145	190	pF

### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			-	32	75	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 30V, I_{D} = 80A$		-	259	528	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 25\Omega$		-	136	282	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4, 5)	-	113	236	ns
Q <sub>g(tot)</sub>	Total Gate Charge at 10V	$V_{DS} = 48V, I_{D} = 80A$		-	57	74	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	V <sub>GS</sub> = 10V		-	15	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		(Note 4, 5)	-	24	-	nC

### **Drain-Source Diode Characteristics**

Is	Maximum Continuous Drain to Source Diode Forward Current			-	-	80	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	-	320	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 80A$		-	-	1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 80A		-	64	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s   (Note 4)$		-	127	-	nC

- $\begin{tabular}{ll} \textbf{Notes:} \\ 1: & Repetitive Rating: Pulse width limited by maximum junction temperature \\ 2: & L = 0.15mH, |_{AS} = 80A, V_{DD} = 50V, R_G = 25\Omega, Starting T_J = 25^{\circ}C \\ 3: & |_{SD} \leq 80A, di/dt \leq 200A[\mu s, V_{DD} \leq BV_{DSS}, Starting T_J = 25^{\circ}C \\ 4: & Pulse Test: Pulse width \leq 300\mu s, Duty Cycle \leq 2\% \\ 5: & Essentially Independent of Operating Temperature Typical Characteristics \\ \end{tabular}$

### **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

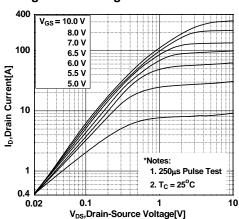


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

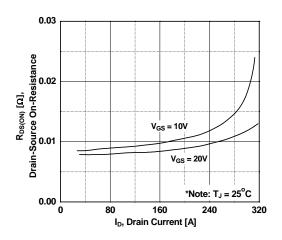


Figure 5. Capacitance Characteristics

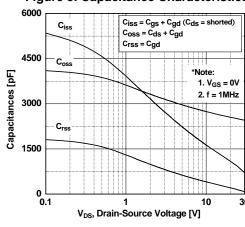


Figure 2. Transfer Characteristics

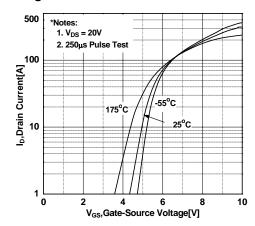


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

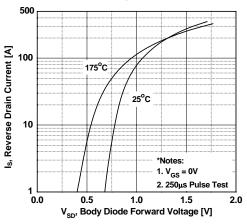
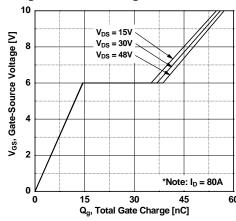


Figure 6. Gate Charge Characteristics



### Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

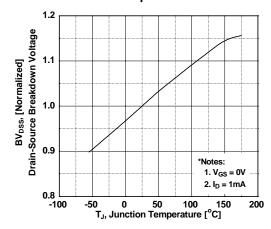


Figure 8. On-Resistance Variation vs. Temperature

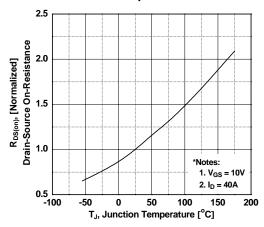


Figure 9. Maximum Safe Operating Area

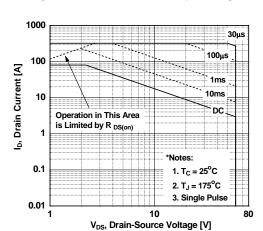


Figure 10. Maximum Drain Current vs. Case Temperature

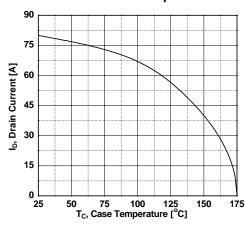
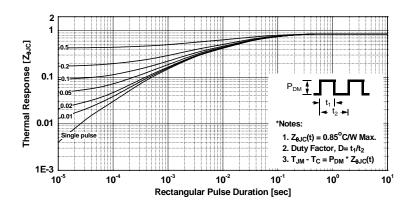
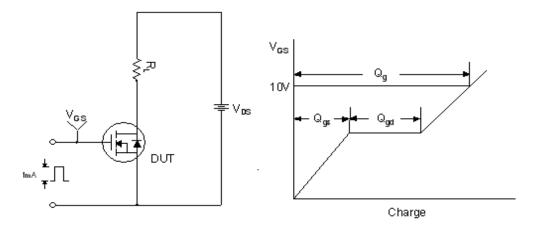


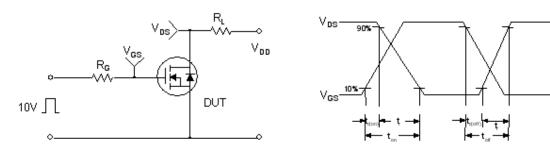
Figure 11. Transient Thermal Response Curve



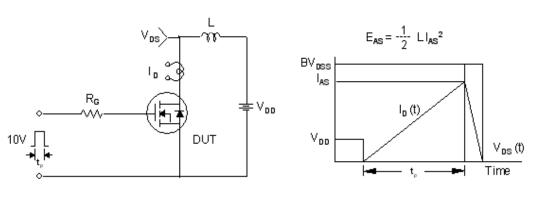
### **Gate Charge Test Circuit & Waveform**

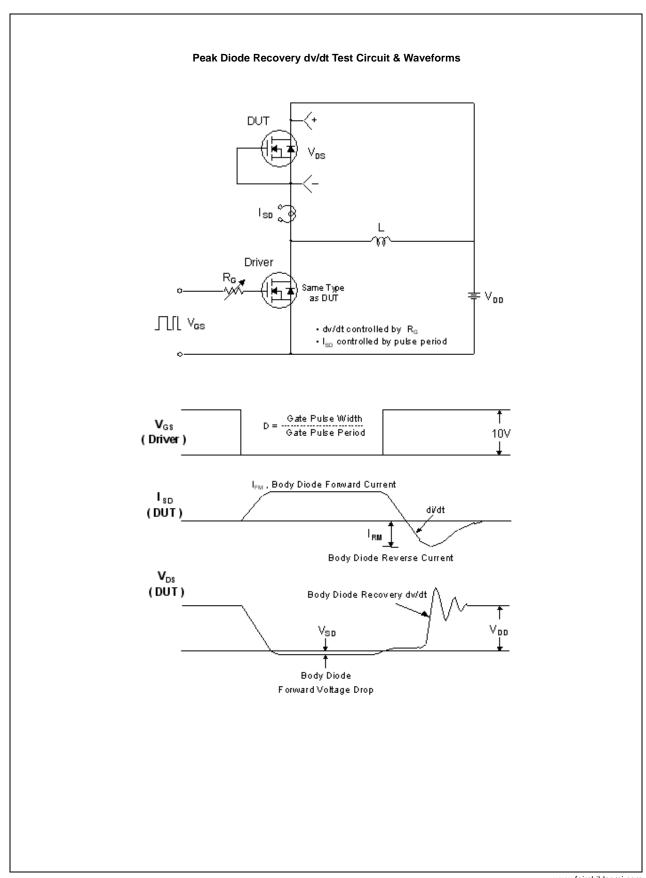


### **Resistive Switching Test Circuit & Waveforms**



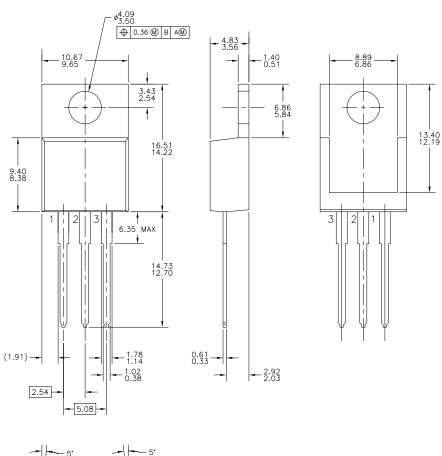
### **Unclamped Inductive Switching Test Circuit & Waveforms**

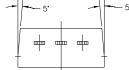




### **Mechanical Dimensions**

### TO-220





Dimensions in Millimeters



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